

ISMTH / ICOIM 2025 Program at a Glance

Date	Time	Schedule					
May 25 (Sunday)	14:00~21:00	Registration					
May 26 (Monday)	09:00~09:30	Opening Ceremony					
	09:30~09:45	In memory of Professor Zhu Li					
	09:45~10:25	Plenary: Precision metrology: beyond bulk optics Xiangqian (Jane) Jiang, University of Huddersfield, The United Kingdom					
	10:25~10:45	Coffee Break & Group Photo					
	10:45~11:25	Plenary: The new paradigms of manufacturing advancement Fengzhou Fang, Tianjin University, University College Dublin, China					
	11:25~12:05	Plenary: Towards super-resolution optical measurement for precision surface inspection Satoru Takahashi, The University of Tokyo, Japan					
	12:05~13:30	Lunch Time / Poster Session					
	13:30~18:00	Session A (Tianmen Hall)	Session B (Jingzhou Hall)	Session C (Qianjiang Hall)	Session D (Qianjiang Hall)	Session E (Shennongjia Hall)	Session F (Dingxiang Hall)
		Keynote Invited Oral					
	18:30~20:00	Dinner Time					
	19:00~21:00	ICMI Member Meeting (Upon Invitation)					
May 27 (Tuesday)	08:30~09:00	Registration					
	09:00~09:40	Plenary: Brain-inspired information photonics for life Min Gu, University of Shanghai for Science and Technology, China					
	09:40~10:20	Plenary: State-of-the-art of optical metrology for precision manufacturing Wei Gao, Tohoku University, Japan					
	10:20~11:00	Plenary: Ultrafast photonics for ultra-precision metrology and manufacturing (UPM2) Young-Jin Kim, Korea Advanced Institute of Science and Technology, South Korea					
	11:00~12:00	Poster Session					
	12:00~13:15	Lunch Time					
	13:30~18:00	Session A (Tianmen Hall)	Session B (Jingzhou Hall)	Session C (Qianjiang Hall)	Session D (Qianjiang Hall)	Session D+ E (Shennongjia Hall)	Session B+F (Dingxiang Hall)
		Keynote Invited Oral					
	18:30~20:00	Banquet					
May 28 (Wednesday)	09:00~11:30	Visit the Hubei Provincial Museum					

ISMTH / ICOIM 2025 Program

Session A May 26 (Monday)

Venue: Tianmen Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Hung-Fei Kuo	Enhancement in scatterometry for overlay process control	National Taiwan University of Science and Technology, Taipei, China
13:55-14:15	Invited	Kai Meng	Optimized optical metrology for lithography overlay control	Nanjing University of Aeronautics & Astronautics, China
14:15-14:35	Invited	Zhongliang Li	X-ray diffraction topography and its application in semiconductor wafer performance testing	Shanghai Advanced Research Institute, Chinese Academy of Sciences, China
14:35-14:55	Invited	Shanyong Chen	Towards atom-accuracy measurement of optical aspheres and freeform surfaces	National University of Defense Technology, China
14:55-15:15	Oral	Xin Xu	Research on ultra-precision laser heterodyne interferometry with picometer-level sensitivity for displacement measurement	Tsinghua University, China
15:15-15:35	Oral	Yuchu Qin	Abstracting prediction of surface roughness in laser powder bed fusion using logical reasoning and category theory	University of Huddersfield, The United Kingdom
15:35-16:00	Coffee Break			
16:00-16:20	Invited	Weibo Wang	Coherent fourier scatterometry combined with high-order signal demodulation for nanoparticle detection	Harbin Institute of Technology, China
16:20-16:40	Invited	Zhipeng Xu	An in-situ flow verifier for semiconductor process gases based on dynamic pVTt	China Jiliang University, China
16:40-17:00	Invited	Hao Jiang	Diffraction based IC overlay metrology: instrumentation and method	Huazhong University of Science and Technology, China
17:00-17:20	Oral	Kaiping Guo	Research on angular displacement sensing method of linear frequency-modulated eddy current time grating	Chongqing University of Technology, China
17:20-17:40	Oral	Han Tong	Calibration of elliptical retarders in dual-rotating compensator Mueller matrix spectroscopic ellipsometry	Huaqiao University, China
17:40-18:00	Oral	Wenhao Teng	A cylindrical two-dimensional capacitive sensor based on splicing technology	Chongqing University of Technology, China

ISMTH / ICOIM 2025 Program

Session A May 27 (Tuesday)

Venue: Tianmen Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Zhengbao Yang	Piezoelectric materials and ultrasound energy harvesting for medical implants	Hong Kong University of Science and Technology, Hongkong, China
13:55-14:15	Invited	Nan Lin	Research development and applications of extreme ultraviolet (EUV) light sources	Shanghai Institute of Optics and Fine Mechanics, Chinese Academy of Sciences, China
14:15-14:35	Invited	Biao Deng	Three X-ray imaging beamlines at SSRF and their applications on IC	Shanghai Advanced Research Institute, Chinese Academy of Sciences, China
14:35-14:55	Invited	Shifeng Guo	Integrated flexible ultrasonic actuators and sensors for multi-scale damage detection and imaging	Shenzhen Institutes of Advanced Technology, Chinese Academy of Sciences, China
14:55-15:15	Oral	Shaohui Qin	Design and fabrication of novel CMUTs with T-shaped cavities	Xi'an Jiaotong University, China
15:15-15:35	Oral	Zhuojiang Nan	Parameter optimization method for multi-mirror structured laser triangulation system based on the combination of network generation and random inspiration	Shanghai Jiao Tong University, China
15:35-16:00	Coffee Break			
16:00-16:20	Invited	Tianliang Li	Optical fiber distal multidimensional force sensing for surgical robot	Wuhan University of Technology, China
16:20-16:40	Invited	Yufu Qu	TSOM and its application in micro-nano critical dimension measurement and defect inspection	Beihang University, China
16:40-17:00	Invited	Yibin Tian	Implicit wafer plane inspection of photomasks using a lithography-aware end-to-end deep neural network	Shenzhen University, China
17:00-17:20	Oral	Kai Wang	Efficient multi-defect sensitivity analysis of overlay targets	Nanjing University of Aeronautics and Astronautics, China
17:20-17:40	Oral	Jing Hu	Robust calibration and alignment strategies for Micro-CSPs	Huazhong University of Science and Technology, China
17:40-18:00	Oral	Hanxu Zou	Experiment research of absolute linear displacement sensor based on eddy current effect	Chongqing University of Technology, China

ISMTH / ICOIM 2025 Program

Session B

May 26 (Monday)

Venue: Jingzhou Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Gaofeng Zheng	Dynamic monitoring and identification system for multi-jet electrospinning with coaxial laser	Xiamen University of Technology, China
13:55-14:15	Invited	So Ito	Comparison of uncertainties in measurement of actual and effective diameters of the tip ball of microprobing system	Toyama Prefectural University, Japan
14:15-14:35	Invited	Jingbiao Chen	Michelson laser for sub-pm resolution displacement measurement	Peking University, China
14:35-14:55	Invited	Liping Yan	Femtosecond laser pulse picking based on mach-zehnder modulator and digital holography microscopy	Zhejiang Sci-Tech University, China
14:55-15:15	Oral	Bixuan Huang	Enhanced geometrical parameters prediction in nanometrology: a hybrid metrology approach using AFM and SEM with artificial neural networks	Shanghai Jiao Tong University, China
15:15-15:35	Oral	Xiaofei Diao	Traceable aspherical interferometric measurement system and waveplate-array detection error analysis	National Institute of Metrology, China
15:35-16:00	Coffee Break			
16:00-16:25	Keynote	Changcai Cui	Measurement of nano-scale subsurface damage layer of wide band-gap semiconductor substrates after ultra-precision machining	China Jiliang University, China
16:25-16:45	Invited	Qiushi Huang	Metrology and manufacture of X-ray reflective optics with nanometer accuracy	Tongji University, China
16:45-17:05	Invited	Yan Dong	Wireless, passive, wearable and flexible biosensors for non-invasive monitoring of key biomarkers in body-fluids	China University of Petroleum (East China), China
17:05-17:25	Invited	Wenhao Li	A random angle error interference eliminating method for grating interferometry measurement based on symmetry littrow structure	Changchun Institute of Optics, Fine Mechanics and Physics, Chinese Academy of Sciences, China
17:25-17:45	Oral	Ziqing Li	Measurement of ultrathin subsurface amorphous damage layer of single-crystal diamond substrates in ultra-precision machining based on ellipsometry	Huaqiao University, China
17:45-18:05	Oral	Yichen Li	A novel method for microsecond dynamic calibration of underwater pressure sensors based on laser-induced cavitation	China Jiliang University, China

ISMTH / ICOIM 2025 Program

Session B

May 27 (Tuesday)

Venue: Jingzhou Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Yasuhiro Mizutan	Measurement uncertainty in machine learning-based measurements	Osaka University, Japan
13:55-14:20	Keynote	Xiaojun Liu	Active structured illumination based optically-sectioned microscopy for complex micro-nano surface measurement	Huazhong University of Science and Technology, China
14:20-14:40	Invited	Pengfei Wang	Scanning nitrogen-vacancy center microscope: the application of quantum sensing and imaging	University of science and technology of China, China
14:40-15:00	Invited	Jixi Lu	SERF atomic magnetometer based on all-optical modulation	Beihang University, China
15:00-15:20	Oral	Tao Li	High accuracy traceability standard for large torque	Shanghai Marine Equipment Research Institute, China
15:20-15:40	Oral	Baowu Zhang	Measurement method of non-contact dual-end without wring for end-face length based on tolansky interference	China Jiliang University, China
15:40-16:00	Coffee Break			
16:00-16:20	Oral	Xiao Deng	Nanoscale length metrology and measurement technology based on natural constants	Tongji University, China
16:20-16:40	Oral	Xiaodong Zhang	The stress calibrators for the wafer thin-film stress measuring instrument	The 13th Institute of China Electronics Technology Group Corporation, China
16:40-17:00	Oral	Lihua Lei	Equivalence investigation of length traceability chain at nanoscale	Shanghai Institute of Measurement and Testing Technology, China
17:00-17:20	Oral	Jianbo Wang	High-accuracy laser wavelength measurement for precision engineering	National Institute of Metrology, China
17:20-17:40	Oral	Chenguang Yin	Stitching interferometry technique applied in pitch pattern self-calibration of a large-area variable-line-spacing scale grating by a Fizeau interferometer	Tohoku University, Japan
17:40-18:00	Oral	Runxi Wu	Innovative non-contact calibration technique for spatial error in industrial robots under variable load conditions utilizing automated rotary mechanism and tri-laser displacement sensors	Xiamen University, China

ISMTH / ICOIM 2025 Program

Session C

May 26 (Monday)

Venue: Xiantao Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Chulmin Joo	Depth-enhanced computational microscopy via co-learned phase filter and image deconvolution	Yonsei University, Korea
13:55-14:15	Invited	Jianglei Di	AI-empowered sparse-angle CT reconstruction	Guangdong University of Technology, China
14:15-14:35	Invited	Peng Gao	Super-resolution fluorescence microscopy and quantitative phase microscopy	Xidian University, China
14:35-14:55	Oral	Qingyu Ma	Efficient fringe projection absolute phase recovery based on dynamic fringe convolution	Qingdao University of Science and Technology, China
14:55-15:15	Oral	Zhicheng Yang	Research on low frequency electromagnetic signal demodulation based on frequency estimation optimization	Northwestern Polytechnical University, China
15:15-15:35	Oral	Yifan Liu	High-speed 3D measurement based on RGB multi-angle Time-multiplexed fringe projection and deep learning	Nanjing University of Science and Technology, China
15:35-16:00	Coffee Break			
16:00-16:25	Keynote	Shin Usuki	Computational optical microscopy enables rapid 3D imaging with improved resolution	Shizuoka University, Japan
16:25-16:45	Invited	Zibang Zhang	Single-pixel optical “fire extinguisher”	Jinan University, China
16:45-17:05	Invited	Caojin Yuan	Single-shot High-fidelity OAM spectrum measurement via neural network-based wavefront correction	Nanjing Normal University, China
17:05-17:25	Oral	Yunyi Chen	A two-step metrology method of collector mirror for EUV lithography	Shanghai Institute of Optics and Fine Mechanics, Chinese Academy of Sciences, China
17:25-17:45	Oral	Zexu Liu	Resolution-enhanced High-dynamic-Range ptychography via unsupervised neural network	Shanghai Institute of Optics and Fine Mechanics, Chinese Academy of Sciences, China
17:45-18:05	Oral	Yongan Wen	Cell classification in digital holographic flow cytometry via direct hologram analysis using deep learning	China University of Petroleum (East China), China

ISMTH / ICOIM 2025 Program

Session C

May 27 (Tuesday)

Venue: Xiantao Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Ruqiang Yan	Signal processing informed neural network for intelligent fault diagnosis	Xi'an Jiaotong University, China
13:55-14:20	Keynote	Chao Zuo	High-speed 3D imaging and metrology: from classical fringe projection to deep learning approaches	Nanjing University of Science and Technology, China
14:20-14:40	Invited	Xiaojun Liang	Data-driven single-frame structured light 3D reconstruction methodology, system and demonstration	Pengcheng Laboratory, China
14:40-15:00	Invited	Ruitao Yang	Crosstalk error correction for high-precision phase measurement in laser interferometry	Harbin Institute of Technology, China
15:00-15:20	Invited	Haoyang Yu	Deep learning-enabled laser spectroscopy for quantitative chemical composition measurement	Central South University, China
15:20-15:40	Oral	Hao Wang	Deep learning-driven high dynamic range structured light for accurate 3D reconstruction	Tsinghua Shenzhen International Graduate School, China
15:40-16:00	Coffee Break			
16:00-16:20	Oral	Cong Liu	Transformer-based monocular depth estimation with attention enhancement for volatile kiln burden surface	Tsinghua Shenzhen International Graduate School, China
16:20-16:40	Oral	Chuangchuang Chen	Diffraction-based computational spectrometry with fancy application in broadband CDI	Hefei University of Technology, China
16:40-17:00	Oral	Zixuan Han	Deep learning-based zero-order elimination for enhanced spatial resolution in single-shot imaging	China University of Petroleum (East China), China
17:00-17:20	Oral	Zhiqi Li	PCANet: polarization-sensitive cross-attention multimodal target detection algorithm	Tsinghua Shenzhen International Graduate School, China
17:20-17:40	Oral	Yifan Liu	High-speed 3D measurement based on RGB multi-angle time-multiplexed fringe projection and deep learning	Nanjing University of Science and Technology, China

ISMTH / ICOIM 2025 Program
Session D
May 26 (Monday)

Venue: Qianjiang Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Guanhao Wu	Frequency-comb-based distance measurement	Tsinghua University, China
13:55-14:15	Invited	Fumin Zhang	Precision 3D measurement based on Multi-Line LiDAR	Tianjin University, China
14:15-14:35	Invited	Hongfang Chen	High-precision optimization method for multi-station layout of the laser tracer	Beijing University of Technology, China
14:35-14:55	Invited	Kai Ni	Free-running dual-comb system for precise measurement	Shenzhen International Graduate School, China
14:55-15:15	Invited	Xinghui Li	Towards atomic manufacturing: multi-dimensional heterodyne grating interferometer	Shenzhen International Graduate School China
15:15-15:35	Oral	Menghan Yang	Design and implementation of multi-channel dual-frequency laser source for grating interferometer	Tsinghua University, China
15:35-16:00	Coffee Break			
16:00-16:20	Oral	Xiangjun Kong	Deep learning-based multi-frequency phase unwrapping for single-shot composite fringe projection profilometry	University of Nottingham, The United Kingdom
16:20-16:40	Oral	Wenxin Jia	Research on key technologies of null interferometer based on point source array for testing freeform surface	Nanjing University of Science and Technology, China
16:40-17:00	Oral	Ki-Nam Joo	Surface figure measurements by radial shearing interferometry using a geometric phase lens	Chosun University, South Korea
17:00-17:20	Oral	Pengbo Zhao	A compact multi-beam collimation method based on prism arrays and two-dimensional reflective gratings	Shenzhen International Graduate School China
17:20-17:40	Oral	Joonho You	The study for measuring the warpage of wafer and chip for HBM and Advanced packaging process	Nexensor Incorporated, South Korea
17:40-18:00	Oral	Xinyuan Guo	Measurement of reflectivity and refractive index based on frequency domain Analysis of coherence scanning interferometry.	Tianjin University, China

ISMTH / ICOIM 2025 Program
Session D
May 27 (Tuesday)

Venue: Qianjiang Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Xiangchao Zhang	Generalized deflectometry for the measurement of semi-specular freeform surfaces	Fudan University, China
13:55-14:15	Invited	Dawei Tang	Surface metrology using dispersive optical sensors	University of Huddersfield, The United Kingdom
14:15-14:35	Invited	Tukun Li	The paradigm shift of the ISO GPS standard system driven by digital manufacturing	University of Huddersfield, The United Kingdom
14:35-14:55	Invited	Jingtao Dong	Laser scanning “point-to-line” confocal probe for dark-field scattering imaging of surface and bulk defects	Hefei University of Technology, China
14:55-15:15	Invited	Chengfu Ma	Scanning probe manipulation and friction measurement of nanodroplets confined by two-dimensional materials	Lanzhou Institute of Chemical Physics, Chinese Academy of Sciences, China
15:15-15:35	Invited	Athanasios Pappas	Functional correlation analysis between the surface height parameters and the mechanical properties of a surface	University of Nottingham, The United Kingdom
15:35-16:00	Coffee Break			
16:00-16:20	Invited	Masaki Michihata	3-dimensional measurement based on laser induced fluorescence	The University of Tokyo, Japan
16:20-16:40	Invited	Tianqi Gu	Robust processing of measurement dataset for complex surfac	Fuzhou University, China
16:40-17:00	Invited	Yi Wang	Coherent tomographic microscopy for three-dimensional topographic measurement	Shanghai Institute of Optics and Fine Mechanics, Chinese Academy of Sciences, China
17:00-17:20	Oral	Shuai Xue	Surface form interferometry for X-ray mirrors with atomic accuracy	National University of Defense Technology, China
17:20-17:40	Oral	Hongling Luo	An efficient adaptive fringe projection framework for high dynamic range 3D measurement with reduced pattern requirement and accurate coordinate mapping	Shanghai Jiao Tong University, China
17:40-18:00	Oral	Runzhou Hou	Topographic spatial resolution assessment for coherence scanning interferometry based on 3D transfer function	Shanghai Jiao Tong University, China

ISMTH / ICOIM 2025 Program
Session E
May 26 (Monday)

Venue: Shennongjia Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Ryo Sato	Surface encoders for multi-axis displacement measurement with a scale grating	Tohoku University, Japan
13:55-14:15	Invited	Sangen Zhao	Anisotropic optical crystal materials	Quantum Science Center of Guangdong, Hongkong Macao Greater Bay Area, China
14:15-14:35	Invited	Anli Yang	Analysis and characterization of compound semiconductor materials	Hubei Jiufengshan Laboratory, China
14:35-14:55	Oral	Yue Ma	Polylactic acid plastic internal depth prediction using thermal imaging and a variational autoencoder	Shenzhen University, China
14:55-15:15	Oral	Yifan Wang	Frequency-swept feedback interferometry for noncooperative-target ranging	Tsinghua University, China
15:15-15:35	Oral	Anbo Wang	Distributed optical fiber sensing based on weak reflecting serial fiber bragg gratings	Virginia Polytechnic Institute and State University, The United States
15:35-16:00	Coffee Break			
16:00-16:20	Invited	Tao Jiang	A calibration and location optimization method for combined tracking-based optical measurement	Suqian University, China
16:20-16:40	Oral	Xiaonan Geng	Lightweight extraction method for structural feature detection in large-scale aircraft panels	Nanjing University of Aeronautics and Astronautics, China
16:40-17:00	Oral	Sen Wang	Height measurement of bumps based on microscopic fringe projection profilometry	Tianjin University of Technology, China
17:00-17:20	Oral	Zhanwu Xie	All-fiber laser self-mixing interferometry for signal enhancement with phase-shifted fiber Bragg grating	Nanjing Normal University, China
17:20-17:40	Oral	Haijun Xi	Study of brillouin-kerr frequency comb based on MgF2 microcavities	Nanchang Hangkong University, China

ISMTH / ICOIM 2025 Program
Session E
May 27 (Tuesday)

Venue: Shennongjia Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Yuki Shimizu	Calibration of diffraction scale gratings for precision positioning	Hokkaido University, Japan
13:55-14:15	Invited	Xiaoyan Cui	Structures for self-assembled cellulose nanoparticles by Mueller matrix analysis	East China Normal University, China
14:15-14:35	Invited	Jiamin Liu	Characterization of semiconductor materials under multiple physics fields using Mueller matrix ellipsometry	Huazhong University of Science and Technology, China
14:35-14:55	Oral	Zhenqi Wang	Microscopic piezoelectric characterization of self-assembled biomaterials	The Hong Kong University of Science and Technology, Hong Kong, China
14:55-15:15	Oral	He Ying	Time and space-resolved raman for measuring the thermal properties of 2D heterostructures	Tianjin university, China
15:15-15:35	Oral	Hyeokin Kang	Long-term AM noise-free optical communication over a 1.3 km free-space atmospheric link	Korea Advanced Institute of Science and Technology, South Korea
15:35-16:00	Coffee Break			
16:00-16:20	Invited	Lihua Peng	Spatially polarization modulated snapshot fourier plane ellipsometry via conoscopic interference for thin-film metrology	Huazhong University of Science and Technology, China
16:20-16:40	Oral	Zizheng Wang	Non-destructive depth measurement of Through Glass Via (TGV) using NIR interferometric spectroscopy	Tianjin University, China
16:40-17:00	Oral	Chu Huy Hoang	Nonlinear optical characterization of semiconductor wafers via femtosecond laser-induced Third Harmonic Generation (THG)	Korea Advanced Institute of Science and Technology, South Korea
17:00-17:20	Oral	Naoya Tashiro	Development of a palm-sized optical head for the calibration of a diffraction scale grating	Hokkaido University, Japan
17:20-17:40	Oral	Yifu Wan	High-precision measurement of surface topography and thickness of transparent curved samples based on interferometric spectroscopy	Tianjin University , China
17:40-18:00	Oral	Guangcanlan Yang	Full-pipeline differentiable ray-tracing modeling for bi-prism phase measuring deflectometry	Soochow University, China

ISMTH / ICOIM 2025 Program
Session F
May 26 (Monday)

Venue: Dingxiang Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Xiaoli Liu	Multi-scale fringe structured light 3D measurement	Shenzhen University, China
13:55-14:15	Invited	Linghui Yang	Research on multi-AGV collaborative transportation technology based on light-controlled positioning	Tianjin University, China
14:15-14:35	Invited	Zhenqi Niu	High-dynamic monoscopic deflectometry research and application for low-spatial-frequency and mid-spatial-frequency error measurement of complex surfaces	Shanghai Institute of Optics and Fine Mechanics, Chinese Academy of Sciences, China
14:35-14:55	Invited	Wei Wu	A node backtracking-based sub-supersynchronous oscillation observation method in radial networks	Electric Power Research Institute CSG, China
14:55-15:15	Invited	Mingxing Jiao	Optimum design of synthetic-wave absolute-distance interferometer using two-cavity dual-frequency Nd:YAG laser	Xi'an University of Technology, China
15:15-15:35	Invited	Yongjia Xu	Automatic area scanning method for form measuring of freeform specular surfaces based on robotic phase measuring deflectometry	University of Huddersfield, The United Kingdom
15:35-16:00	Coffee Break			
16:00-16:20	Oral	Yubo Ni	Structured light reconstruction with surface reflection inhomogeneity suppression	Hebei University of Technology, China
16:20-16:40	Oral	Yanling Li	Robotic arm operated automatic aera scanning phase measuring stitching deflectometry calibration method	Hebei University of Technology, China
16:40-17:00	Oral	Qinyu Lu	A method to guarantee the measurement accuracy of plane displacement with a hole using eddy current sensors in mechatronics applications	Dalian University of Technology, China
17:00-17:20	Oral	Reza Aulia Rahman	Position controlled photonic nanojet for machining in water medium by second harmonic generation	Osaka University, Indonesia
17:20-17:40	Oral	Yun Zou	Analysis of higher-order geometric errors for laser interferometry towards nanometer measurement	Harbin Institute of Technology, China
17:40-18:00	Oral	Qiming Fan	Laser 3D projection calibration method based on camera-like model and gaussian process regression	Jiangsu University of Science and Technology, China

ISMTH / ICOIM 2025 Program
Session F
May 27 (Tuesday)

Venue: Dingxiang Hall

Time	Activity	Speaker	Title	Affiliation
13:30-13:55	Keynote	Wei Tao	Structural laser intelligent measurement technology and its application in special environments	Shanghai Jiao Tong University, China
13:55-14:20	Keynote	Nikita D. Zviagin	Measurement challenges and artificial intelligence	D.I.Mendeleyev Institute for Metrology, Russia
14:20-14:40	Invited	Yuan Yao	Micro-optical accelerometers based on grating interferometer - status and development	Huazhong University of Science and Technology, China
14:40-15:00	Invited	Jiandong Xie	Multi-heterodyne interferometric absolute distance measurement and applications	Zhejiang Sci-Tech university, China
15:00-15:20	Oral	Shimin Jiao	High-sensitivity opto-mechanical MEMS accelerometer with 10 ng/ $\sqrt{\text{Hz}}$ noise floor and kHz bandwidth	Huazhong University of Science and Technology, China
15:20-15:40	Oral	Xin Xiong	Self-calibration of large-scale planar variable-line-spacing gratings with a conjugate differential interferometric method	Chongqing University of Technology, China
15:40-16:00	Coffee Break			
16:00-16:20	Oral	Jinyang Zou	Photoacoustic frequency comb imaging of metals	Tianjin University, China
16:20-16:40	Oral	Peirui Ji	High-performance photodetectors based on low-dimensional materials	Xi'an Jiaotong University, China
16:40-17:00	Oral	Yanxu Sun	Research on non-uniform error calibration and its effects on CT reconstruction accuracy	Harbin Institue of Technology, China
17:00-17:20	Oral	Xinran Tian	A FSM-based high-accuracy automatic magnetic compensation method for dual-channel SERF magnetometers using in biomedical weak magnetic measurement	Tianjin University, China
17:20-17:40	Oral	Dongfang Zhao	Research on ultra-precision measurement method for sphericity error based on multi-section circular profile data fusion	Harbin Institute of Technology, China